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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

ATTORNEY'S DKT No.
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APPLICATION No.
TBA/371 app of
PCT/FR00/00360

APPLICANT
Agnely et al

FILING DATE
Aug. 20, 2001

GROUP
Unassigned

U.S. PATENT DOCUMENTS

Examiner Initials	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication (MM-DD-YYYY)
	Number	Kind Code (if known)		

FOREIGN PATENT DOCUMENTS

Examiner Initials	Foreign Patent Document		Country	Date of Publication (MM-DD-YYYY)	Translation	
	Number	Kind Code (if known)			Yes	no
my	0 567 214 A		EP	27-10-1993		

NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Include name of author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		
my	FENG L and NG K.Y.S., "Characterization of Styrene Polymerization in Microemulsion by Raman Spectroscopy", <i>COLLOIDS AND SURFACES</i> , 1991, pp. 349-361, vol. 53, no. 3-4; XP002120792 abstract pp. 351-355		
I	CLAYBOURN M et al, "Analysis of Processes in Latex Systems by Fourier Transform Raman Spectroscopy", <i>JOURNAL OF RAMAN SPECTROSCOPY</i> , 1994, pp. 123-129, vol. 25; XP002069189 abstract, p. 123		
	CHANG S.Y. and NAM S.W., "Monitoring Polymerization Reactions by Near-IR Spectroscopy", <i>ACS SYMPOSIUM SERIES: MULTIDIMENSIONAL SPECTROSCOPY OF POLYMERS</i> , 1995, pp. 147-165, vol. 598; XP002120793 pp. 153-159		
	VIVARAT-PERRIN, M.P.; "Le Spectrometre Raman S'Installe En Ligne, A 200 M Des Capteurs", <i>MESURES REGULATION AUTOMATISME</i> , 1 April 1998, pp. 63-66, No. 704; XP000780554, p. 66		
	ADAR F et al, "Raman Spectroscopy for Process/Quality Control", <i>APPLIED SPECTROSCOPY REVIEWS</i> , 1997, pp. 45-101, vol. 32, no. 1/02; XP000695107, ISSN: 0570-4928, p. 58, p. 77		
ms	SAWATZKI J., "FT-Raman-Spektroskopie in-line", <i>CLB CHEMIE IN LABOR UND BIOTECHNIK</i> , 1999, pp. 33-335, vol. 50, no. 9; XP002120794		
Examiner Signature	Tae H Yoon		Date Considered 10-29-03

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. SEND TO: Assistant Commissioner for Patents, Washington, D.C. 20231.

(05/01)